Search Notes				

 Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,325	LEE, JIAHN-LIN
Examiner	Art Unit
 Tai Duong	2871

	SEARCHED					
Cla	ass	Subclass	Date		Examiner	
34	49	139	12/3/2005		TD	
		149				-
		151				
		152				
		153				
		154				
		156	-			
		160				
		190				

INTERFERENCE SEARCHED						
Cla	ess	Subclass	Date		Examiner	
34	19	139	12/3/05		TD	
;		153			-	
		190				
PGPUB text search - 12/03/05, see interference printout		12/3/2005		TD		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM TDB) see search history printout	12/3/2005	TD
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